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		Application Number	10/805,377		VALUE OF THE PROPERTY OF THE P
TRANSMITTAL	Filing Date	09/25/2003			
FORM	First Named Inventor	Jun-Cheng Lai			
(to be used for all correspondence after in	(to be used for all correspondence after initial filing)		1752		
		Examiner Name			
Total Number of Pages in This Submission	31	Attorney Docket Number	LKSP0022USA		
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Fee Transmittal Form Fee Attached Amendment/Reply After Final Affidavlts/declaration(s) Extension of Time Request Express Abandonment Request Information Disclosure Statemen Certified Copy of Priority Document(s) Response to Missing Parts/ Incomplete Application Response to Missing Part under 37 CFR 1.52 or 1.5	Reman	Drawing(s) Licensing-related Papers Petition Petition to Convert to a Provisional Application Power of Attorney, Revocation Change of Correspondence Addr. Ferminal Disclaimer Request for Refund CD, Number of CD(s)	ess	to Technolo Appeal Col Appeals Appeal Col (Appeal Not Proprietary Status Lett	osure(s) (please
	NATURE C	F APPLICANT, ATTORN	EY, OR AGE	NT	
Firm or Individual name Winston Hsu,	Reg. No.	: 41,526	, ,		
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FAX TO: ART UNIT: 1752

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FROM: Winston Hsu, PATENT AGENT, REG. NO.: 41,526

SERIAL NO.: 10/605,377

ATTORNEY DOCKET NO.: LKSP0022USA

SUBJECT: INFORMATION DISCLOSURE STATEMENT

TOTAL PAGES: 33 PAGES (INCLUDING COVER PAGE)

Winston Hsu 2004/08/17

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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Jun-Cheng Lai

5 Filing Date: 09/25/2003

Serial No.: 10/605,377

Art Unit: 1752

Docket No.: LKSP0022USA

Title: METHOD OF IMPROVING A RESOLUTION OF CONTACT

HOLE PATTERNS BY UTILIZING ALTERNATE PHASE

10 SHIFT PRINCIPLE

To: Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

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Subject: Information disclosure statement Under

37C.F.R.\$1.56 and 37C.F.R.\$1.97(b).

Dear Sir:

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This is an Information Disclosure Statement in accordance with the duty to disclose information material to patentability under 37 C.F.R. \$1.56. Applicants wish to make of record the document listed on the accompanying form PTO/SB/08. It is respectfully requested that the Examiner initials the cited reference on the form and that it be made of record in the application and that a copy of the initialed form be sent to Applicants with the next communication from the Examiner.

Since the information disclosure statement is filed

before the mailing of a first Office action on the merits, the requirement set forth in 37 C.F.R.\$1.97(b)(3) is satisfied. The prior art patent contained in the information disclosure statement was cited in communications from the Taiwan Intellectual Property Office on 06/08/2004. Applicant sincerely hopes that the examiner can consider the item contained in the information disclosure statement.

According to the requirement set forth in 37 C.F.R.\$1.98 and M.P.E.P. 609, the applicant is submitting copies of the reference cited by the Taiwan Intellectual Property Office (Taiwan Patent No. 423048, published Feb. 21, 2001) and a concise explanation of the relevance in this application hereinafter.

Taiwan Patent No. 423048 discloses forming a plurality of interconnection patterns 50 having good resolution by utilize an alternating phase shift mask 20 (Please refer to Fig.1 and Fig.2). On the alternating phase shift mask, light permeable regions 20 and light permeable regions 30, having a thickness different from a thickness of the light permeable regions 20, are surrounded by an opaque region. The opaque region 25 comprises interconnection line patterns in the shape of a line and a peripheral protection region. Due to the difference between the thickness of the light permeable regions 20 and 30, light passing through the light permeable regions 20 has a phase shift of 180 30 degrees relative to light passing through the light permeable regions 30. Under the circumstances, diffraction lights are cancelled out from each other

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at the edge of the interconnection patterns 50 to improve a resolution between the adjacent interconnection patterns 50.

- 5 Independent claims 1 and 9 of the present application are repeated here for reference:
 - 1. A lithography method for forming a plurality of closed patterns in a photoresist layer on a substrate, the patterns being isolated from each other and being arranged in an array, the lithography method comprising:

providing a phase shift mask (PSM), wherein the phase shift mask comprises:

a plurality of first phase shift transparent regions;

a plurality of second phase shift transparent regions having a phase shift relative to the first phase shift transparent regions; and

a non-phase shift region, wherein the first
phase shift transparent regions and the second
phase shift transparent regions are regularly
interlaced in an array, and each of the first phase
shift transparent regions and each of the second
phase shift transparent regions are separated by
the non-phase shift region; and

performing an exposure process to form the closed patterns in the photoresist layer, wherein the closed patterns are corresponding to the first phase shift transparent regions and the second phase shift transparent regions.

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9. A lithography method for forming a plurality of closed patterns in a photoresist layer on a substrate, the patterns being isolated from each other and being arranged in an array, the lithography method comprising:

providing a phase shift mask (PSM), wherein the phase shift mask comprises:

a plurality of first phase shift transparent regions;

a plurality of second phase shift transparent regions having a phase shift relative to the first phase shift transparent regions; and

a non-phase shift region, wherein portions of the first phase shift transparent regions and portions of the second phase shift transparent regions are regularly interlaced in an array, and each of the first phase shift transparent regions and each of the second phase shift transparent regions are separated by the non-phase shift region; and

performing an exposure process to form the closed patterns in the photoresist layer, wherein the closed patterns are corresponding to the first phase shift transparent regions and the second phase shift transparent regions.

Compared with Taiwan Patent No. 423048, the present application method of forming the closed patterns in the photoresist layer is to utilize a phase shift mask having the first phase shift transparent regions and the second phase shift transparent regions regularly interlaced in an array. Because the first phase shift

transparent regions and the second phase shift transparent regions are regularly interlaced in an array, diffraction lights are cancelled out from each other along two dimensions to form the closed patterns.

- 5 In Taiwan Patent No. 423048, the light permeable regions 20 and the light permeable regions 30 are regularly interlaced along one dimension. Therefore, the diffraction lights, canceling out from each other at the edge of the interconnection patterns 50, are only along one dimension. In other words, it is impossible to form closed patterns having a good resolution according to the method disclosed by Taiwan Patent No. 423048.
- In summary, the method disclosed by the present application is able to form closed patterns. The method disclosed by Taiwan Patent No. 423048 can only form interconnection line patterns rather than the closed patterns, such as contact hole patterns and a logic cell patterns of a logic circuit.

Since claims 1 and 9 of the present application are substantially different from the prior art patent Taiwan Patent No. 423048, and all other claims are dependent on claims 1 and 9, a quick allowance of the present application is sincerely requested.

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Respectfully Submitted,

5 Windon Hou

Date:

8/10/200g

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10 U.S.A.

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(Please contact me by e-mail if you need a telephone communication and I will return your call promptly.)

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	Application Number	10/605,377		
INFORMATION DISCLOSURE	Filing Date	09/25/2003		
	First Named Inventor	Jun-Cheng Lai		
STATEMENT BY APPLICANT	Art Unit	1752		
(Use as many sheets as necessary)	Examiner Name			
Sheet 1 of 1	Attorney Docket Number	LKSP0022USA		

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		Number-Kind Code ² (************************************	MM-DD-YYYY	Applicant of Cited Decument	Relevant Passages or Relevant Figures Appear	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. Applicant's unique citation designation number (optional). See Kinda Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. Applicant is to place a check mark here if English language Translation is attached.

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